# International IR Rectifier

#### **PRELIMINARY**

# IRL540N

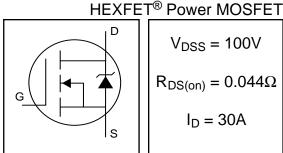
Logic-Level Gate Drive

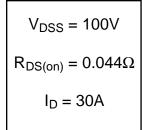
- Advanced Process Technology
- Isolated Package
- High Voltage Isolation = 2.5KVRMS ⑤
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated

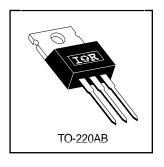
#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	30	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	21	Α
I <sub>DM</sub>	Pulsed Drain Current ①	120	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy②	310	mJ
I <sub>AR</sub>	Avalanche Current①	18	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①	9.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.3	V/ns
$T_J$	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.6	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
				0.044		V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A ④
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.053	Ω	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 18A ④
				0.063		V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 15A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
9 <sub>fs</sub>	Forward Transconductance	14			S	$V_{DS} = 25V, I_{D} = 18A$
	Dunin to Course Lealings Courset			25		V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -16V$
$Q_g$	Total Gate Charge			74		I <sub>D</sub> = 18A
Q <sub>gs</sub>	Gate-to-Source Charge			9.4	nC	$V_{DS} = 5.0V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			38		$V_{GS}$ = 5.0V, See Fig. 6 and 13 @
t <sub>d(on)</sub>	Turn-On Delay Time		11			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		81		200	I <sub>D</sub> = 18A
t <sub>d(off)</sub>	Turn-Off Delay Time		39		ns	$R_G = 5.0\Omega$ , $V_{GS} = 5.0V$
tf	Fall Time		62			$R_D = 2.7\Omega$ , See Fig. 10 $\textcircled{4}$
L <sub>D</sub>	Internal Drain Inductance		4.5		– nH	Between lead,
						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5	_	-	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		1800			$V_{GS} = 0V$
Coss	Output Capacitance		350		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		170			f = 1.0MHz, See Fig. 5

## **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			20		MOSFET symbol	
	(Body Diode)		<del></del> 30	A	showing the		
I <sub>SM</sub>	Pulsed Source Current				400		integral reverse
	(Body Diode) ①⑥	1	120		p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 18A, V <sub>GS</sub> = 0V ④	
t <sub>rr</sub>	Reverse Recovery Time		190	290	ns	$T_J = 25$ °C, $I_F = 18A$	
Q <sub>rr</sub>	Reverse RecoveryCharge		1.1	1.7	μC	di/dt = 100A/µs ④	
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25$ °C, L = 1.9mH  $R_G = 25\Omega$ ,  $I_{AS} = 18$ A. (See Figure 12)

- $\label{eq:loss_def} \begin{tabular}{ll} \Im & I_{SD} \leq 18A, \ di/dt \leq 180A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \\ & T_{J} \leq 175^{\circ}C \end{tabular}$
- ④ Pulse width  $\leq$  300µs; duty cycle  $\leq$  2%

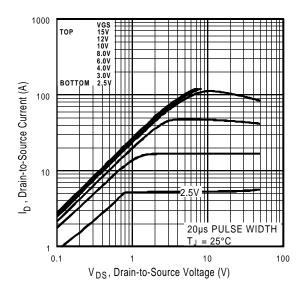


Fig 1. Typical Output Characteristics,  $T_J = 25^{\circ}C$ 

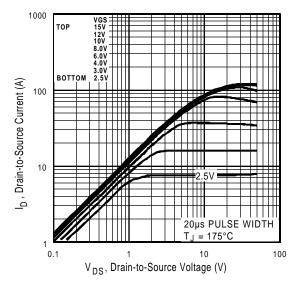


Fig 2. Typical Output Characteristics,  $T_J = 175^{\circ}C$ 

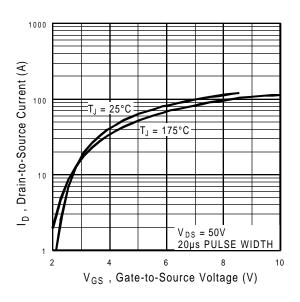
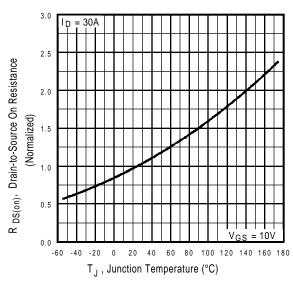
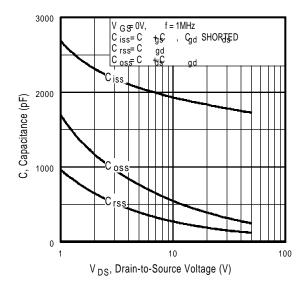


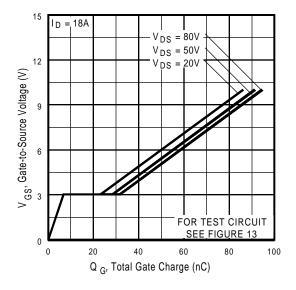
Fig 3. Typical Transfer Characteristics



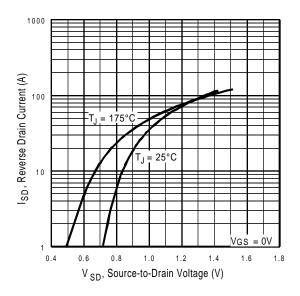
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

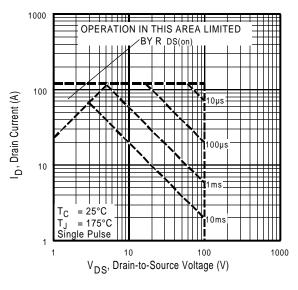
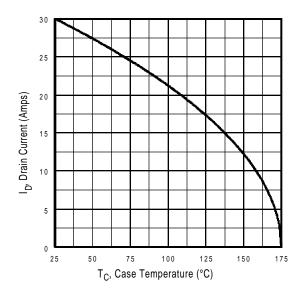


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

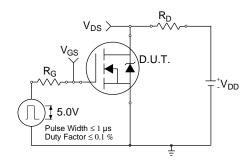


Fig 10a. Switching Time Test Circuit

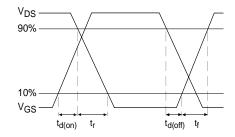


Fig 10b. Switching Time Waveforms

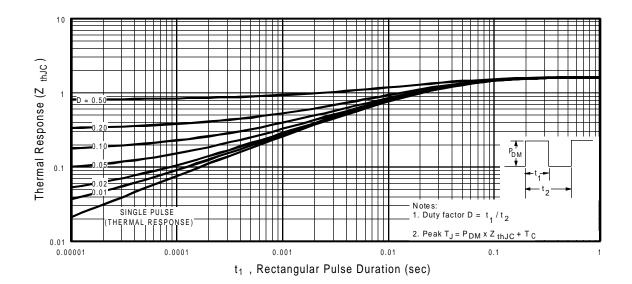


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

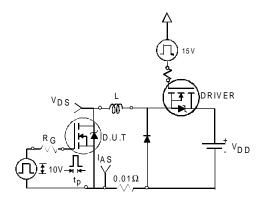


Fig 12a. Unclamped Inductive Test Circuit

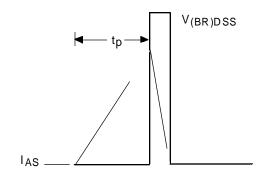


Fig 12b. Unclamped Inductive Waveforms

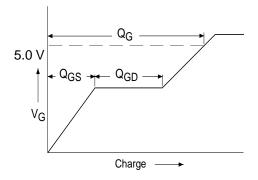
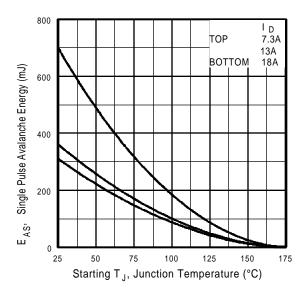


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

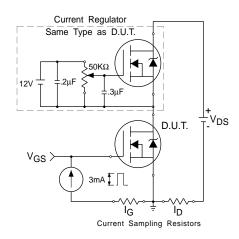
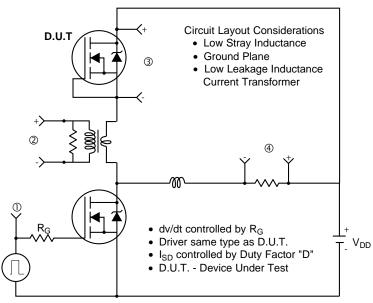


Fig 13b. Gate Charge Test Circuit

# Peak Diode Recovery dv/dt Test Circuit



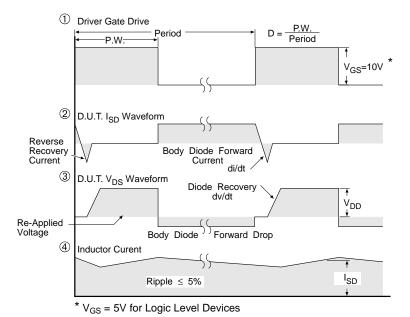
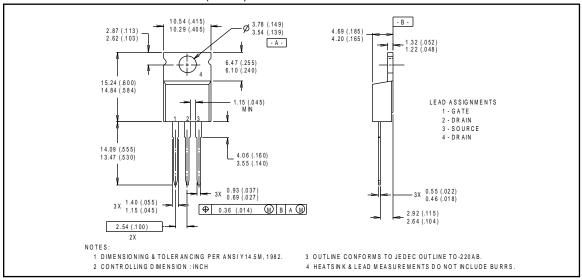


Fig 14. For N-Channel HEXFETS

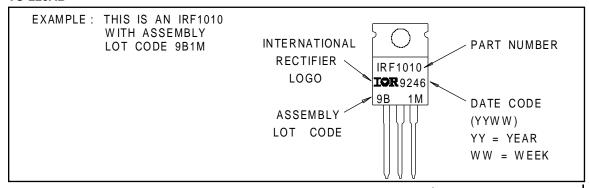
## Package Outline

#### **TO-220AB Outline**

Dimensions are shown in millimeters (inches)



# Part Marking Information



# International TOR Rectifier

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